

54AC/74AC273 Octal D Flip-Flop

General Description

The '273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset ($\overline{MR}$) input load and reset (clear) all flip-flops simultaneously.

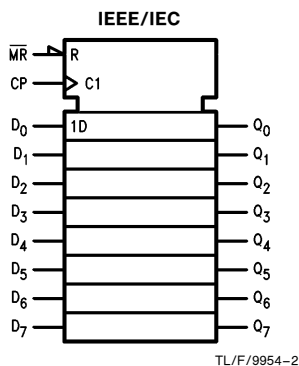
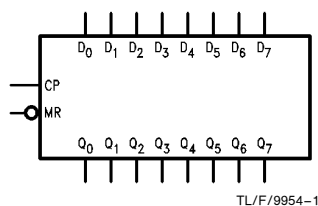
The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output.

All outputs will be forced LOW independently of Clock or Data inputs by a LOW voltage level on the $\overline{MR}$ input. The device is useful for applications where the true output only is required and the Clock and Master Reset are common to all storage elements.

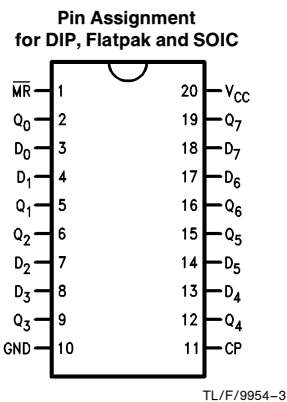
Features

- Ideal buffer for microprocessor or memory
- Eight edge-triggered D flip-flops
- Buffered common clock
- Buffered, asynchronous master reset
- See '377 for clock enable version
- See '373 for transparent latch version
- See '374 for TRI-STATE version
- Outputs source/sink 24 mA
- 'ACT has TTL-compatible inputs
- Standard Military Drawing (SMD)
— 'AC273: 5962-87756

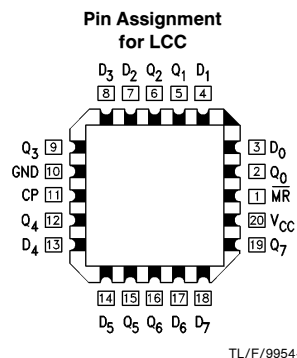
Logic Symbols



Connection Diagrams



Pin Names	Description
D ₀ –D ₇	Data Inputs
$\overline{MR}$	Master Reset
CP	Clock Pulse Input
Q ₀ –Q ₇	Data Outputs



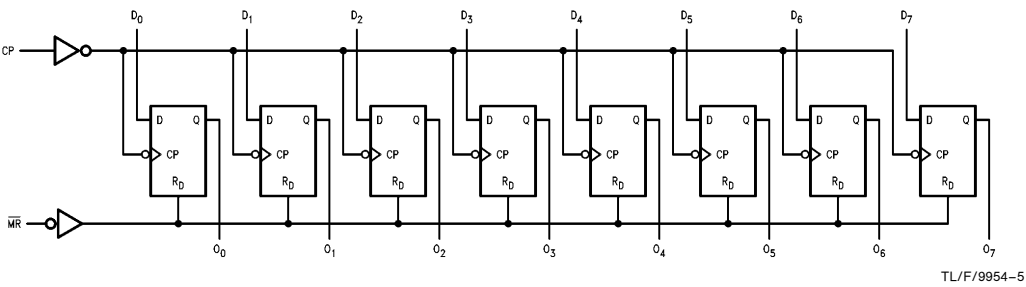
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Mode Select-Function Table

Operating Mode	Inputs			Outputs
	$\overline{MR}$	CP	D_n	Q_n
Reset (Clear)	L	X	X	L
Load '1'	H	↗	H	H
Load '0'	H	↘	L	L

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
↗ = LOW-to-HIGH Transition

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Rating (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5V to +7.0V
DC Input Diode Current (I_{IK})	−20 mA
$V_I = -0.5V$	−20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Input Voltage (V_I)	−0.5V to $V_{CC} + 0.5V$
DC Output Diode Current (I_{OK})	−20 mA
$V_O = -0.5V$	−20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage (V_O)	−0.5V to $V_{CC} + 0.5V$
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	−65°C to +150°C
Junction Temperature (T_J)	
CDIP	175°C
PDIP	140°C

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

Recommended Operating Conditions

Supply Voltage (V_{CC})	2.0V to 6.0V
'AC	
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	
74AC	−40°C to +85°C
54AC	−55°C to +125°C
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
'AC Devices	
V_{IN} from 30% to 70% of V_{CC}	
V_{CC} @ 3.3V, 4.5V, 5.5V	125 mV/ns

DC Characteristics for 'AC Family Devices

Symbol	Parameter	V _{CC} (V)	74AC		54AC		74AC		Units	Conditions
			T _A = +25°C		T _A = −55°C to +125°C		T _A = −40°C to +85°C			
			Typ	Guaranteed Limits						
V _{IH}	Minimum High Level Input Voltage	3.0	1.5	2.1	2.1		2.1		V	V _{OUT} = 0.1V or V _{CC} − 0.1V
		4.5	2.25	3.15	3.15		3.15			
		5.5	2.75	3.85	3.85		3.85			
V _{IL}	Maximum Low Level Input Voltage	3.0	1.5	0.9	0.9		0.9		V	V _{OUT} = 0.1V or V _{CC} − 0.1V
		4.5	2.25	1.35	1.35		1.35			
		5.5	2.75	1.65	1.65		1.65			
V _{OH}	Minimum High Level Output Voltage	3.0	2.99	2.9	2.9		2.9		V	I _{OUT} = −50 μA
		4.5	4.49	4.4	4.4		4.4			
		5.5	5.49	5.4	5.4		5.4			
		3.0		2.56	2.4		2.46		V	*V _{IN} = V _{IL} or V _{IH} −12 mA I _{OH} −24 mA −24 mA
		4.5		3.86	3.7		3.76			
		5.5		4.86	4.7		4.76			
V _{OL}	Maximum Low Level Output Voltage	3.0	0.002	0.1	0.1		0.1		V	I _{OUT} = 50 μA
		4.5	0.001	0.1	0.1		0.1			
		5.5	0.001	0.1	0.1		0.1			
		3.0		0.36	0.50		0.44		V	*V _{IN} = V _{IL} or V _{IH} 12 mA I _{OL} 24 mA 24 mA
		4.5		0.36	0.50		0.44			
		5.5		0.36	0.50		0.44			
I _{IN}	Maximum Input Leakage Current	5.5		±0.1	±1.0		±1.0		μA	V _I = V _{CC} , GND

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

DC Characteristics for 'AC Family Devices (Continued)

Symbol	Parameter	V _{CC} (V)	74AC		54AC		74AC		Units	Conditions
			T _A = +25°C		T _A = −55°C to +125°C		T _A = −40°C to +85°C			
			Typ	Guaranteed Limits						
I _{OLD}	†Minimum Dynamic Output Current	5.5			50		75		mA	V _{OLD} = 1.65V Max
I _{OHD}		5.5			−50		−75		mA	V _{OHD} = 3.85V Min
I _{CC}	Maximum Quiescent Supply Current	5.5		4.0	80.0		40.0		μA	V _{IN} = V _{CC} or GND

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note: I_{IN} and I_{CC} @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC}.
I_{CC} for 54AC @ 25°C is identical to 74AC @ 25°C.

AC Electrical Characteristics

Symbol	Parameter	V _{CC} [*] (V)	74AC			54AC		74AC		Units
			T _A = +25°C C _L = 50 pF			T _A = −55°C to +125°C C _L = 50 pF		T _A = −40°C to +85°C C _L = 50 pF		
			Min	Typ	Max	Min	Max	Min	Max	
f _{max}	Maximum Clock Frequency	3.3 5.0	90 140	125 175		75 90		75 125		MHz
t _{PLH}	Propagation Delay Clock to Output	3.3 5.0	4.0 3.0	7.0 5.5	12.5 9.0	1.0 1.0	15.0 11.0	3.0 2.5	14.0 10.0	ns
t _{PHL}	Propagation Delay Clock to Output	3.3 5.0	4.0 3.0	7.0 5.0	13.0 10.0	1.0 1.0	16.0 11.5	3.5 2.5	14.5 11.0	ns
t _{PHL}	Propagation Delay MR to Output	3.3 5.0	4.0 3.0	7.0 5.0	13.0 10.0	1.0 1.0	16.0 11.5	3.5 2.5	14.0 10.5	ns

*Voltage Range 3.3 is 3.3V ±0.3V

Voltage Range 5.0 is 5.0V ±0.5V

AC Operating Requirements

Symbol	Parameter	V _{CC} * (V)	74AC		54AC	74AC	Units
			T _A = +25°C C _L = 50 pF		T _A = −55°C to +125°C C _L = 50 pF	T _A = −40°C to +85°C C _L = 50 pF	
			Typ	Guaranteed Minimum			
t _s	Setup Time, HIGH or LOW Data to CP	3.3 5.0	3.5 2.5	5.5 4.0	8.0 5.0	6.0 4.5	ns
t _h	Hold Time, HIGH or LOW Data to CP	3.3 5.0	−2.0 −1.0	0 1.0	0 1.0	0 1.0	ns
t _w	Clock Pulse Width HIGH or LOW	3.3 5.0	3.5 2.5	5.5 4.0	6.5 5.0	6.0 4.5	ns
t _w	MR Pulse Width HIGH or LOW	3.3 5.0	2.0 1.5	5.5 4.0	10.0 6.5	6.0 4.5	ns
t _{rec}	Recovery Time MR to CP	3.3 5.0	1.5 1.0	3.5 2.0	6.0 4.0	4.5 3.0	ns

*Voltage Range 3.3 is 3.3V ±0.3V

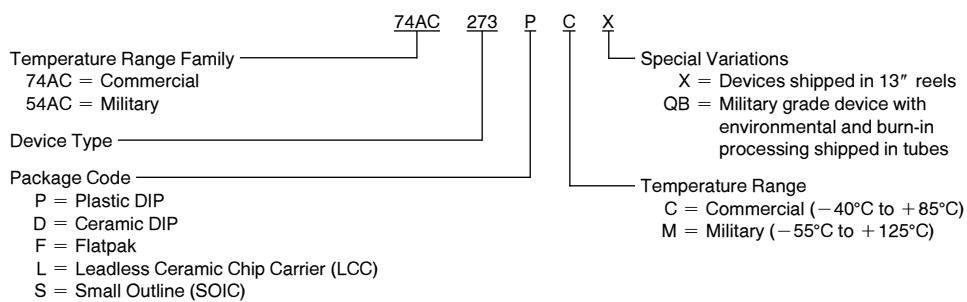
Voltage Range 5.0 is 5.0V ±0.5V

Capacitance

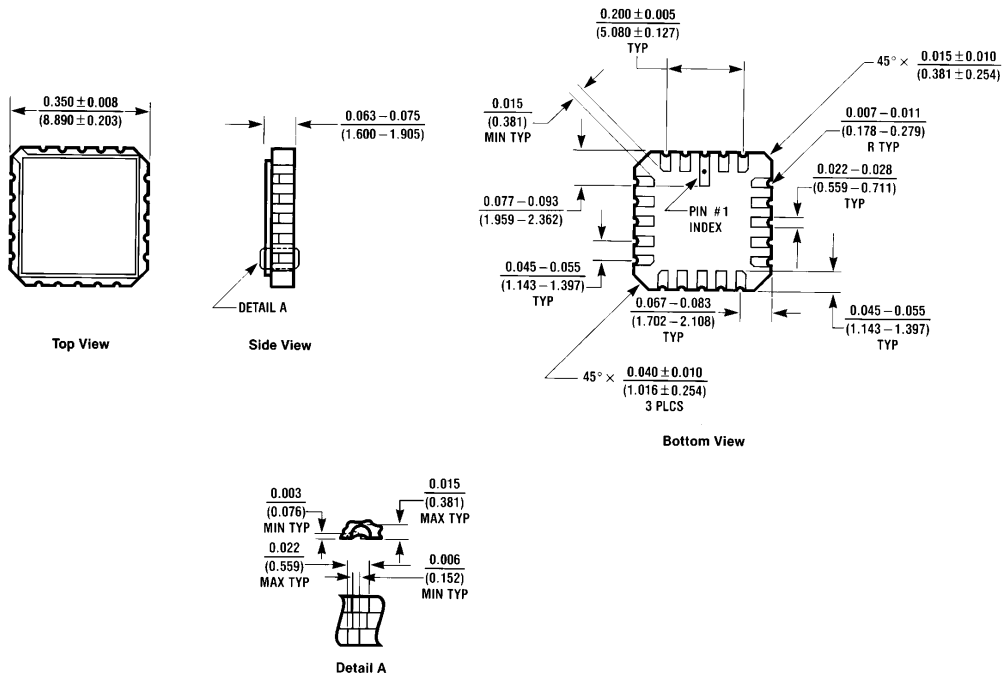
Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	$V_{CC} = \text{Open}$
C_{PD}	Power Dissipation Capacitance	50.0	pF	$V_{CC} = 5.0V$

Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

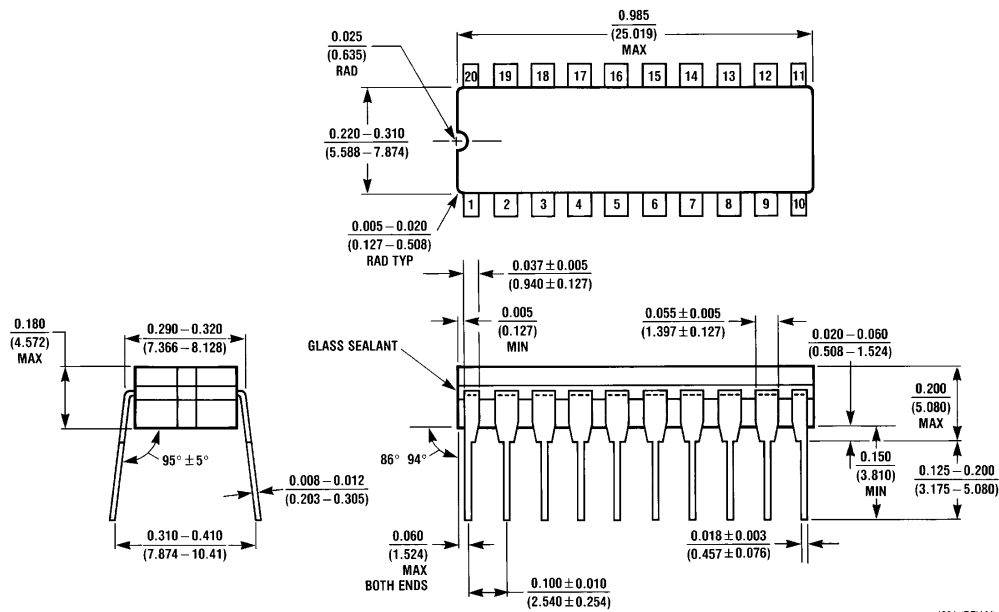


Physical Dimensions inches (millimeters)



E20A (REV D)

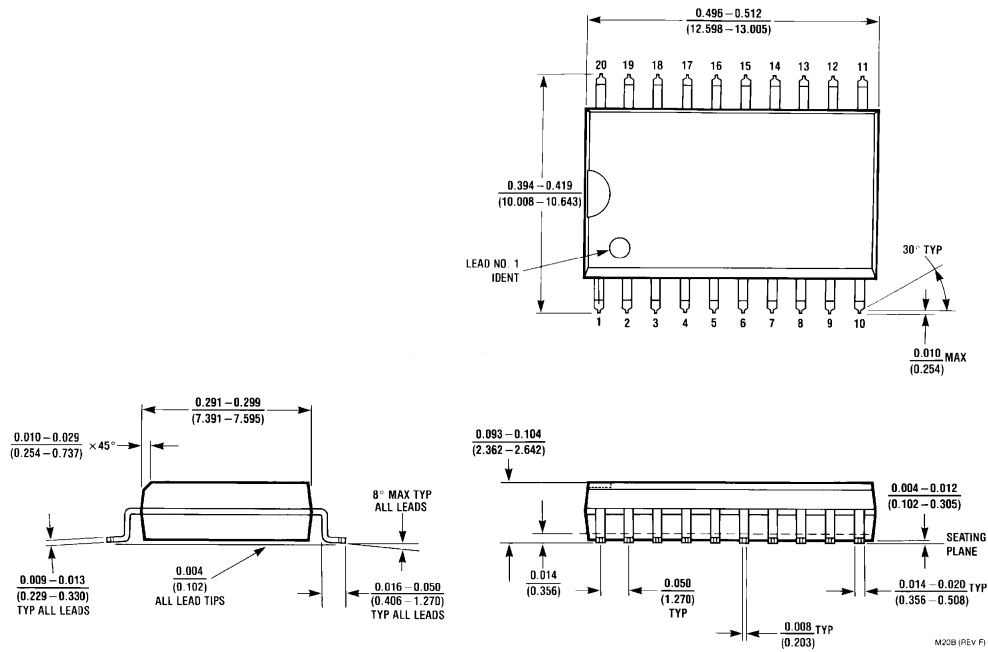
20 Terminal Ceramic Leadless Chip Carrier (L) NS Package Number E20A



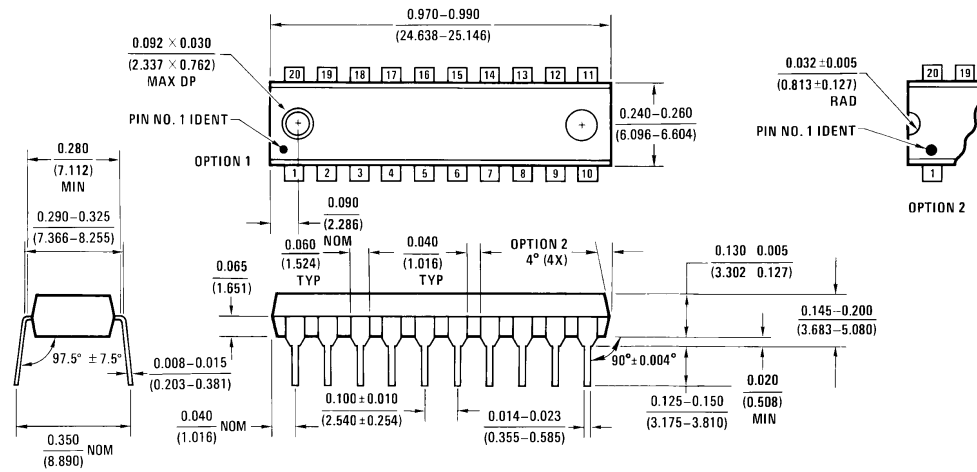
J20A (REV M)

20 Lead Ceramic Dual-In-Line Package (D) NS Package Number J20A

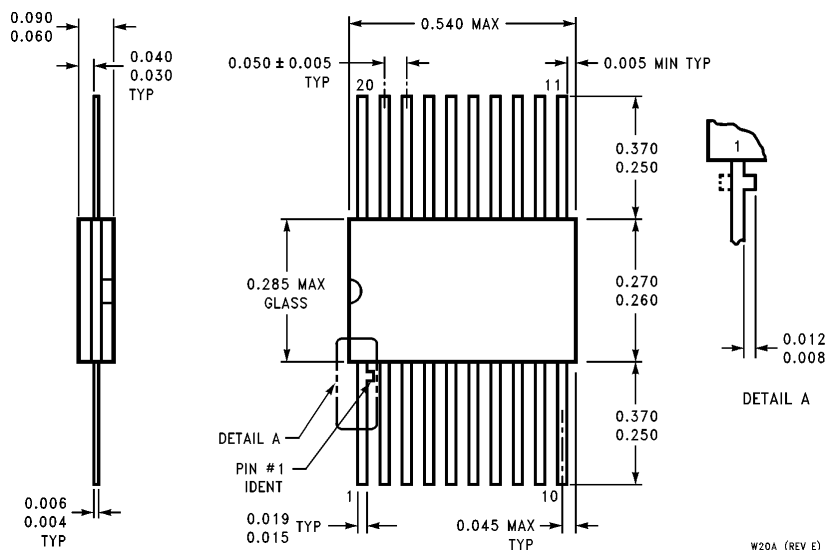
Physical Dimensions inches (millimeters) (Continued)



**20 Lead Small Outline Integrated Circuit (S)
NS Package Number M20B**



**20 Lead Plastic Dual-In-Line Package (P)
NS Package Number N20B**

Physical Dimensions inches (millimeters) (Continued)

**20 Lead Ceramic Flatpak (F)
NS Package Number W20A**

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